Notice of References Cited Application/Control No. 10/713,794 Examiner Duc M. Nguyen Applicant(s)/Patent Under Reexamination KARR ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0099303 A1	05-2003	Birru et al.	375/265
*	В	US-5,949,822 A	09-1999	Hancharik, David J.	375/242
*	С	US-5,442,646 A	08-1995	Chadwick et al.	714/795
*	D	US-2005/0052571 A1	03-2005	Ghosh, Monisha	348/426.1
*	E	US-2003/0105913 A1	06-2003	Lee, Jae-Hong	711/5
*	F	US-6,671,284 B1	12-2003	Yonge et al.	370/462
*	G	US-2005/0201368 A1	09-2005	Periyalwar et al.	370/356
*	Η	US-2002/0090938 A1	07-2002	Dharia et al.	455/422
*	I	US-6,567,471 B1	05-2003	Yoshinari, Hiromi	375/240.26
*	J	US-5,694,404	12-1997	Huang, Wei-Hung	714/751
*	K	US-4,692,894	09-1987	Bernis, Gerald L.	710/57
*	L	US-5,548,814 A	08-1996	Lorang et al.	370/310
*	М	US-6,101,168	08-2000	Chen et al.	370/228

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 95/22233	08-1995	PCT	Bessette	H04Q 11/04
	0					
	Р					·
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	
	v	
	w	
	×	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.